


<b>Search Notes</b>  	<b>Application/Control No.</b>  10567571	<b>Applicant(s)/Patent Under Reexamination</b>  BOEHLAND ET AL.
	<b>Examiner</b>  Christopher S Kim	<b>Art Unit</b>  3752

SEARCHED			
Class	Subclass	Date	Examiner
239	96, 533.2, 533.8, 533.9	8/13/08	CK

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner